

# MMPQ3467

## Quad Memory Driver Transistor PNP Silicon

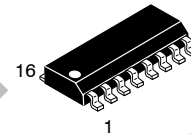


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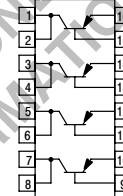
<http://onsemi.com>

### MAXIMUM RATINGS

Rating	Symbol	Value		Unit
Collector–Emitter Voltage	$V_{CEO}$	–40		Vdc
Collector–Base Voltage	$V_{CB}$	–40		Vdc
Emitter–Base Voltage	$V_{EB}$	–5.0		Vdc
Collector Current — Continuous	$I_C$	–1.0		Adc
		Each Transistor	Four Transistors Equal Power	
Power Dissipation @ $T_A = 25^\circ\text{C}$ Derate above $25^\circ\text{C}$	$P_D$	0.52 4.2	1.2 9.6	W mW/°C
Power Dissipation @ $T_C = 25^\circ\text{C}$ Derate above $25^\circ\text{C}$	$P_D$	1.0 8.0	2.5 20	W mW/°C
Operating and Storage Junction Temperature Range	$T_J, T_{stg}$	–55 to +150		°C



CASE 751B–05, STYLE 4  
SO–16



### ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Collector–Emitter Breakdown Voltage <sup>(1)</sup> ( $I_C = -10\text{ mAdc}, I_E = 0$ )	$V_{(BR)CEO}$	–40	—	—	Vdc
Collector–Base Breakdown Voltage ( $I_C = -10\ \mu\text{Adc}, I_E = 0$ )	$V_{(BR)CBO}$	–40	—	—	Vdc
Emitter–Base Breakdown Voltage ( $I_E = -10\ \mu\text{Adc}, I_C = 0$ )	$V_{(BR)EBO}$	–5.0	—	—	Vdc
Collector Cutoff Current ( $V_{CB} = -30\text{ Vdc}, I_E = 0$ )	$I_{CBO}$	—	—	–200	nAdc
Emitter Cutoff Current ( $V_{EB} = -3.0\text{ Vdc}, I_C = 0$ )	$I_{EBO}$	—	—	–200	nAdc

1. Pulse Test: Pulse Width  $\leq 300\ \mu\text{s}$ ; Duty Cycle  $\leq 2.0\%$ .

Preferred devices are ON Semiconductor recommended choices for future use and best overall value.

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## ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ unless otherwise noted) (Continued)

Characteristic	Symbol	Min	Typ	Max	Unit
<b>ON CHARACTERISTICS</b>					
DC Current Gain <sup>(1)</sup> ( $I_C = -500 \text{ mAdc}$ , $V_{CE} = -1.0 \text{ Vdc}$ )	$h_{FE}$	20	—	—	—
Collector–Emitter Saturation Voltage <sup>(1)</sup> ( $I_C = -500 \text{ mAdc}$ , $I_B = -50 \text{ mAdc}$ )	$V_{CE(sat)}$	—	-0.23	-0.5	Vdc
Base–Emitter Saturation Voltage <sup>(1)</sup> ( $I_C = -500 \text{ mAdc}$ , $I_B = -50 \text{ mAdc}$ )	$V_{BE(sat)}$	—	-0.9	-1.2	Vdc
<b>DYNAMIC CHARACTERISTICS</b>					
Current–Gain — Bandwidth Product ( $I_C = -50 \text{ mAdc}$ , $V_{CE} = -10 \text{ Vdc}$ , $f = 100 \text{ MHz}$ )	$f_T$	—	190	—	MHz
Output Capacitance ( $V_{CB} = -10 \text{ Vdc}$ , $I_E = 0$ , $f = 1.0 \text{ MHz}$ )	$C_{ob}$	—	10	—	pF
Input Capacitance ( $V_{EB} = -0.5 \text{ Vdc}$ , $I_C = 0$ , $f = 1.0 \text{ MHz}$ )	$C_{ib}$	—	55	—	pF
<b>SWITCHING CHARACTERISTICS</b>					
Turn–On Time ( $I_C = -500 \text{ mAdc}$ , $I_{B1} = -50 \text{ mAdc}$ )	$t_{on}$	—	20	—	ns
Turn–Off Time ( $I_C = -500 \text{ mAdc}$ , $I_{B1} = I_{B2} = -50 \text{ mAdc}$ )	$t_{off}$	—	60	—	ns

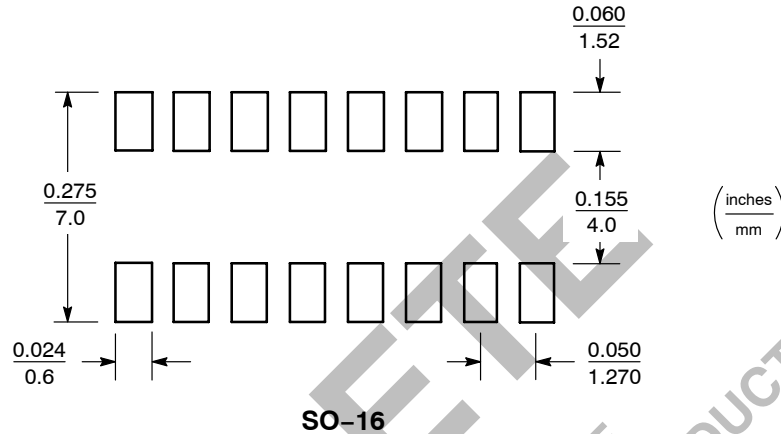
1. Pulse Test: Pulse Width  $\leq 300 \mu\text{s}$ ; Duty Cycle  $\leq 2.0\%$ .

## INFORMATION FOR USING THE SO-16 SURFACE MOUNT PACKAGE

### MINIMUM RECOMMENDED FOOTPRINT FOR SURFACE MOUNTED APPLICATIONS

Surface mount board layout is a critical portion of the total design. The footprint for the semiconductor packages must be the correct size to insure proper solder connection

interface between the board and the package. With the correct pad geometry, the packages will self align when subjected to a solder reflow process.



### SO-16 POWER DISSIPATION

The power dissipation of the SO-16 is a function of the pad size. This can vary from the minimum pad size for soldering to a pad size given for maximum power dissipation. Power dissipation for a surface mount device is determined by  $T_{J(max)}$ , the maximum rated junction temperature of the die,  $R_{\theta JA}$ , the thermal resistance from the device junction to ambient, and the operating temperature,  $T_A$ . Using the values provided on the data sheet for the SO-16 package,  $P_D$  can be calculated as follows:

$$P_D = \frac{T_{J(max)} - T_A}{R_{\theta JA}}$$

The values for the equation are found in the maximum ratings table on the data sheet. Substituting these values into the equation for an ambient temperature  $T_A$  of 25°C, one can calculate the power dissipation of the device which in this case is 1.0 watt.

$$P_D = \frac{150^\circ\text{C} - 25^\circ\text{C}}{125^\circ\text{C/W}} = 1.0 \text{ watt}$$

The 125°C/W for the SO-16 package assumes the use of the recommended footprint on a glass epoxy printed circuit board to achieve a power dissipation of 1.0 watt. There are other alternatives to achieving higher power dissipation from the SO-16 package. Another alternative would be to use a ceramic substrate or an aluminum core board such as Thermal Clad™. Using a board material such as Thermal Clad, an aluminum core board, the power dissipation can be doubled using the same footprint.

### SOLDERING PRECAUTIONS

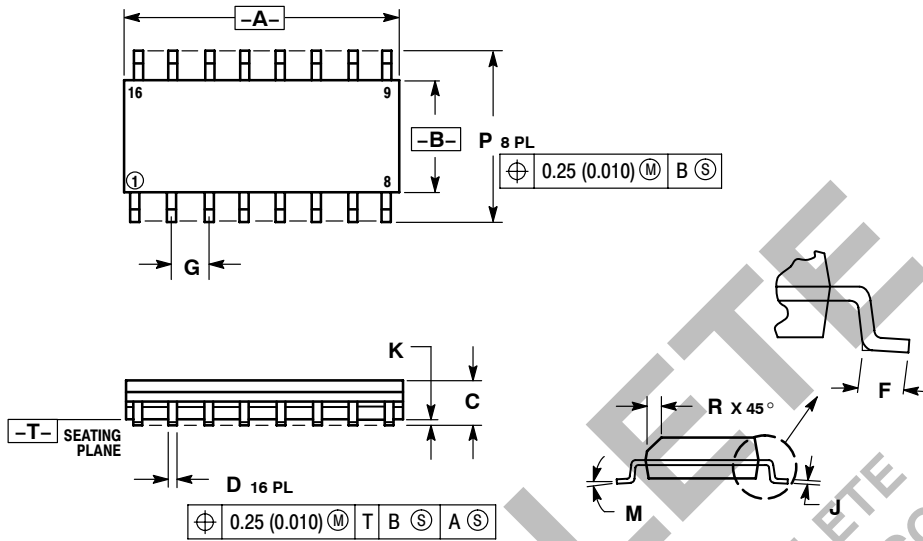
The melting temperature of solder is higher than the rated temperature of the device. When the entire device is heated to a high temperature, failure to complete soldering within a short time could result in device failure. Therefore, the following items should always be observed in order to minimize the thermal stress to which the devices are subjected.

- Always preheat the device.
  - The delta temperature between the preheat and soldering should be 100°C or less.\*
  - When preheating and soldering, the temperature of the leads and the case must not exceed the maximum temperature ratings as shown on the data sheet. When using infrared heating with the reflow soldering method, the difference shall be a maximum of 10°C.
  - The soldering temperature and time shall not exceed 260°C for more than 10 seconds.
  - When shifting from preheating to soldering, the maximum temperature gradient shall be 5°C or less.
  - After soldering has been completed, the device should be allowed to cool naturally for at least three minutes. Gradual cooling should be used as the use of forced cooling will increase the temperature gradient and result in latent failure due to mechanical stress.
  - Mechanical stress or shock should not be applied during cooling.
- \* Soldering a device without preheating can cause excessive thermal shock and stress which can result in damage to the device.

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## PACKAGE DIMENSIONS

### CASE 751B-05 SO-16 ISSUE J



#### NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER.
- DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	9.80	10.00	0.386	0.393
B	3.80	4.00	0.150	0.157
C	1.35	1.75	0.054	0.068
D	0.35	0.49	0.014	0.019
F	0.40	1.25	0.016	0.049
G	1.27 BSC		0.050 BSC	
J	0.19	0.25	0.008	0.009
K	0.10	0.25	0.004	0.009
M	0°	7°	0°	7°
P	5.80	6.20	0.229	0.244
R	0.25	0.50	0.010	0.019

#### STYLE 4:

- PIN 1:
- COLLECTOR, DYE #1
  - COLLECTOR, #1
  - COLLECTOR, #2
  - COLLECTOR, #2
  - COLLECTOR, #3
  - COLLECTOR, #3
  - COLLECTOR, #4
  - COLLECTOR, #4
  - BASE, #4
  - EMITTER, #4
  - BASE, #3
  - EMITTER, #3
  - BASE, #2
  - EMITTER, #2
  - BASE, #1
  - EMITTER, #1

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